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(54) **TWO-LEVEL ERROR CORRECTING CODE
WITH SHARING OF CHECK-BITS**

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(71) Applicant: **Taiwan Semiconductor
Manufacturing Company, Ltd.,
Hsinchu (TW)**

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(72) Inventor: **Shih-Lien Linus Lu, Hsinchu (TW)**

(73) Assignee: **Taiwan Semiconductor
Manufacturing Company, Ltd.,
Hsinchu (TW)**

(57)

ABSTRACT

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A memory device includes: a memory device configured to store data bits to be written to the memory device; and a memory controller. The memory controller includes: a first level error correction code (ECC) circuit coupled to the memory device, wherein the first level ECC circuit is configured to generate a first plurality of first level check bits corresponding to the data bits based on a first error detection scheme; and a second level ECC circuit coupled to the memory device, wherein the second level ECC circuit is configured to generate a second plurality of second level check bits corresponding to both the data bits and the first plurality of first level check bits based on a first error correction scheme.

